

| | | | |
|-----------------------------------|---------------------------------------|--|-------------|
| Notice of References Cited | Application/Control No. 10/758,268 | Applicant(s)/Patent Under Reexamination KATOI ET AL. | |
| | Examiner Dien Tran | Art Unit 3748 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| | A | US-3,771,921 | 11-1973 | Rohde et al. | 417/12 |
| | B | US-5,088,463 | 02-1992 | Affeldt et al. | 123/459 |
| | C | US-5785025 | 07-1998 | Yoshiume et al. | 123/497 |
| | D | US-5,233,830 | 08-1993 | Takeshima et al. | 60/278 |
| | E | US-5979157 | 08-1997 | Kinugasa et al. | 60/289 |
| | F | US-6192678 | 02-2001 | Tachibana | 60/289 |
| | G | US-5331809 | 07-1994 | Takeshima et al. | 60/289 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.